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Intel - 5AGZME7H2F35I3LN Datasheet



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Understanding <u>Embedded - FPGAs (Field</u> <u>Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	21225
Number of Logic Elements/Cells	450000
Total RAM Bits	40249344
Number of I/O	534
Number of Gates	
Voltage - Supply	0.82V ~ 0.88V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	1152-BBGA, FCBGA
Supplier Device Package	1152-FBGA (35x35)
Purchase URL	https://www.e-xfl.com/product-detail/intel/5agzme7h2f35i3ln

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

1/O Standard	andard			V _{SWING(DC)} (V)		V _{X(AC)} (V)			V _{SV}	_{WING(AC)} (V)
	Min	Тур	Max	Min	Мах	Min	Тур	Max	Min	Max
SSTL-125	1.19	1.25	1.31	0.18	(15)	V _{CCIO} /2 – 0.15	V _{CCIO} /2	V _{CCIO} /2 + 0.15	2(V _{IH(AC)} – V _{REF})	$2(V_{IL(AC)} - V_{REF})$

Differential HSTL and HSUL I/O Standards

Table 1-18: Differential HSTL and HSUL I/O Standards for Arria V Devices

I/O Standard	,	V _{CCIO} (V))	V _{DI}	_{F(DC)} (V)		$V_{X(AC)}(V)$			$V_{CM(DC)}(V)$		V	_{DIF(AC)} (V)
	Min	Тур	Max	Min	Max	Min	Тур	Max	Min	Тур	Max	Min	Мах
HSTL-18 Class I, II	1.71	1.8	1.89	0.2	_	0.78	_	1.12	0.78	_	1.12	0.4	_
HSTL-15 Class I, II	1.425	1.5	1.575	0.2	—	0.68	—	0.9	0.68	—	0.9	0.4	—
HSTL-12 Class I, II	1.14	1.2	1.26	0.16	V _{CCIO} + 0.3	_	$0.5 imes V_{ m CCIO}$		$0.4 \times V_{ m CCIO}$	$0.5 imes V_{ m CCIO}$	$0.6 \times V_{ m CCIO}$	0.3	V _{CCIO} + 0.48
HSUL-12	1.14	1.2	1.3	0.26	0.26	$\begin{array}{c} 0.5 \times \\ \mathrm{V}_{\mathrm{CCIO}} - \\ 0.12 \end{array}$	0.5 × V _{CCIO}	$\begin{array}{c} 0.5 \times \\ \mathrm{V}_{\mathrm{CCIO}} \\ + \ 0.12 \end{array}$	$0.4 \times V_{\rm CCIO}$	0.5 × V _{CCIO}	0.6 × V _{CCIO}	0.44	0.44

Differential I/O Standard Specifications

Table 1-19: Differential I/O Standard Specifications for Arria V Devices

Differential inputs are powered by V_{CCPD} which requires 2.5 V.



Symbol/Description	Condition	Transceiver Speed Grade 4		Transceiver Speed Grade 6			Unit	
Symbol/Description	Condition	Min	Тур	Max	Min	Тур	Max	onic
Inter-transceiver block transmitter channel-to- channel skew ⁽³⁹⁾	×N PMA bonded mode			500		_	500	ps

Table 1-24: CMU PLL Specifications for Arria V GX and SX Devices

Symbol/Description	Transceiver S	peed Grade 4	Transceiver S	peed Grade 6	Unit
Symbol/Description	Min	Мах	Min	Мах	Ont
Supported data range	611	6553.6	611	3125	Mbps
fPLL supported data range	611	3125	611	3125	Mbps

Table 1-25: Transceiver-FPGA Fabric Interface Specifications for Arria V GX and SX Devices

Symbol/Description	Transceiver Spee	ed Grade 4 and 6	Unit		
Symbol Description	Min	Max	Ont		
Interface speed (single-width mode)	25	187.5	MHz		
Interface speed (double-width mode)	25	163.84	MHz		

Related Information

- CTLE Response at Data Rates > 3.25 Gbps across Supported AC Gain and DC Gain on page 1-35
- CTLE Response at Data Rates \leq 3.25 Gbps across Supported AC Gain and DC Gain on page 1-36
- Arria V GT, GX, ST, and SX Device Family Pin Connection Guidelines Provides more information about the power supply connection for different data rates.



⁽³⁹⁾ This specification is only applicable to channels on one side of the device across two transceiver banks.

Transceiver Specifications for Arria V GT and ST Devices

Table 1-26: Reference Clock Specifications	for Arria V GT and ST Devices
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Symbol/Description	Condition	Tran	sceiver Speed Gra	ide 3	llait
Symbol/Description	Condition	Min Typ		Мах	Onic
Supported I/O standards	1.2 V PCML, 1.4 VPCML,	1.5 V PCML, 2.5	V PCML, Differe	ential LVPECL ⁽⁴⁰⁾	, HCSL, and LVDS
Input frequency from REFCLK input pins	_	27		710	MHz
Rise time	Measure at ±60 mV of differential signal ⁽⁴¹⁾			400	ps
Fall time	Measure at ±60 mV of differential signal ⁽⁴¹⁾			400	ps
Duty cycle	_	45		55	%
Peak-to-peak differential input voltage	—	200		300 ⁽⁴²⁾ /2000	mV
Spread-spectrum modulating clock frequency	PCI Express (PCIe)	30		33	kHz
Spread-spectrum downspread	PCIe		0 to -0.5%		_
On-chip termination resistors	—		100		Ω
V _{ICM} (AC coupled)	—	—	1.2		V
V _{ICM} (DC coupled)	HCSL I/O standard for the PCIe reference clock	250		550	mV



⁽⁴⁰⁾ Differential LVPECL signal levels must comply to the minimum and maximum peak-to-peak differential input voltage specified in this table.

REFCLK performance requires to meet transmitter REFCLK phase noise specification. (41)

⁽⁴²⁾ The maximum peak-to peak differential input voltage of 300 mV is allowed for DC coupled link.

CTLE Response at Data Rates ≤ 3.25 Gbps across Supported AC Gain and DC Gain

Figure 1-3: CTLE Response at Data Rates ≤ 3.25 Gbps across Supported AC Gain and DC Gain for Arria V GX, GT, SX, and ST Devices





Symbol	Parameter	Condition	Min	Тур	Max	Unit
t (67)	Period jitter for dedicated clock output	$F_{OUT} \ge 100 \text{ MHz}$	—	_	175	ps (p-p)
OUTPJ_DC	in integer PLL	$F_{OUT} < 100 \text{ MHz}$	—		17.5	mUI (p-p)
+ (67)	Period jitter for dedicated clock output	$F_{OUT} \ge 100 \text{ MHz}$	_		250 ⁽⁶⁸⁾ , 175 ⁽⁶⁹⁾	ps (p-p)
^L FOUTPJ_DC	in fractional PLL	F _{OUT} < 100 MHz	_		25 ⁽⁶⁸⁾ , 17.5 ⁽⁶⁹⁾	mUI (p-p)
t (67)	Cycle-to-cycle jitter for dedicated clock	$F_{OUT} \ge 100 \text{ MHz}$	—	_	175	ps (p-p)
OUTCCJ_DC	output in integer PLL	F _{OUT} < 100 MHz	_		17.5	mUI (p-p)
t(67)	Cycle-to-cycle jitter for dedicated clock	$F_{OUT} \ge 100 \text{ MHz}$	_		250 ⁽⁶⁸⁾ , 175 ⁽⁶⁹⁾	ps (p-p)
FOUTCCJ_DC	output in fractional PLL	F _{OUT} < 100 MHz	—		25 ⁽⁶⁸⁾ , 17.5 ⁽⁶⁹⁾	mUI (p-p)
t (67)(70)	Period jitter for clock output on a	$F_{OUT} \ge 100 \text{ MHz}$	_		600	ps (p-p)
OUTPJ_IO	regular I/O in integer PLL	F _{OUT} < 100 MHz	—		60	mUI (p-p)
t (67)(68)(70)	Period jitter for clock output on a	$F_{OUT} \ge 100 \text{ MHz}$	—		600	ps (p-p)
FOUTPJ_IO	regular I/O in fractional PLL	F _{OUT} < 100 MHz	_	_	60	mUI (p-p)
t (67)(70)	Cycle-to-cycle jitter for clock output on	$F_{OUT} \ge 100 \text{ MHz}$	—		600	ps (p-p)
LOUTCCJ_IO	a regular I/O in integer PLL	F _{OUT} < 100 MHz	—	_	60	mUI (p-p)
t	Cycle-to-cycle jitter for clock output on	$F_{OUT} \ge 100 \text{ MHz}$	—		600	ps (p-p)
t _{FOUTCCJ_IO} (⁶⁷⁾⁽⁶⁸⁾⁽⁷⁰⁾	a regular I/O in fractional PLL	F _{OUT} < 100 MHz	_		60	mUI (p-p)



⁽⁶⁷⁾ Peak-to-peak jitter with a probability level of 10⁻¹² (14 sigma, 99.99999999974404% confidence level). The output jitter specification applies to the intrinsic jitter of the PLL, when an input jitter of 30 ps is applied. The external memory interface clock output jitter specifications use a different measurement method and are available in Memory Output Clock Jitter Specification for Arria V Devices table.

⁽⁶⁸⁾ This specification only covered fractional PLL for low bandwidth. The f_{VCO} for fractional value range 0.05–0.95 must be \geq 1000 MHz.

⁽⁶⁹⁾ This specification only covered fractional PLL for low bandwidth. The f_{VCO} for fractional value range 0.20–0.80 must be \geq 1200 MHz.

⁽⁷⁰⁾ External memory interface clock output jitter specifications use a different measurement method, which are available in Memory Output Clock Jitter Specification for Arria V Devices table.

Figure 1-7: Timing Diagram for oe and dyn_term_ctrl Signals



Duty Cycle Distortion (DCD) Specifications

Table 1-47: Worst-Case DCD on Arria V I/O Pins

The output DCD cycle only applies to the I/O buffer. It does not cover the system DCD.

Symbol	-I3,	-C4	–C5, –I5		-(6	Unit
Symbol	Min	Max	Min	Max	Min	Max	Unit
Output Duty Cycle	45	55	45	55	45	55	%

HPS Specifications

This section provides HPS specifications and timing for Arria V devices.

For HPS reset, the minimum reset pulse widths for the HPS cold and warm reset signals (HPS_nRST and HPS_nPOR) are six clock cycles of HPS_CLK1.



Symbol	Description	Min	Тур	Max	Unit
T _{din_end}	Input data valid end	$(2 + R_{delay}) \times T_{qspi_clk} - 1.21^{(85)}$			ns

Figure 1-8: Quad SPI Flash Timing Diagram

This timing diagram illustrates clock polarity mode 0 and clock phase mode 0.



Related Information

Quad SPI Flash Controller Chapter, Arria V Hard Processor System Technical Reference Manual

Provides more information about Rdelay.

SPI Timing Characteristics

Table 1-52: SPI Master Timing Requirements for Arria V Devices

The setup and hold times can be used for Texas Instruments SSP mode and National Semiconductor Microwire mode.

Symbol	Description	Min	Max	Unit
T _{clk}	CLK clock period	16.67	—	ns
T _{su}	SPI Master-in slave-out (MISO) setup time	8.35 (86)	—	ns

 $^{^{(85)}}$ R_{delay} is set by programming the register <code>qspiregs.rddatacap</code>. For the SoC EDS software version 13.1 and later, Altera provides automatic Quad SPI calibration in the preloader. For more information about R_{delay}, refer to the Quad SPI Flash Controller chapter in the Arria V Hard Processor System Technical Reference Manual.



Figure 1-11: SD/MMC Timing Diagram



Related Information

Booting and Configuration Chapter, Arria V Hard Processor System Technical Reference Manual Provides more information about CSEL pin settings in the SD/MMC Controller CSEL Pin Settings table.

USB Timing Characteristics

PHYs that support LPM mode may not function properly with the USB controller due to a timing issue. It is recommended that designers use the MicroChip USB3300 PHY device that has been proven to be successful on the development board.

Table 1-55: USB Timing Requirements for Arria V Devices

Symbol	Description	Min	Тур	Мах	Unit
T _{clk}	USB CLK clock period	—	16.67	_	ns
T _d	CLK to USB_STP/USB_DATA[7:0] output delay	4.4	_	11	ns
T _{su}	Setup time for USB_DIR/USB_NXT/USB_DATA[7:0]	2			ns
T _h	Hold time for USB_DIR/USB_NXT/USB_DATA[7:0]	1			ns



HPS JTAG Timing Specifications

Symbol	Description	Min	Max	Unit
t _{JCP}	TCK clock period	30	_	ns
t _{JCH}	TCK clock high time	14		ns
t _{JCL}	TCK clock low time	14		ns
t _{JPSU (TDI)}	TDI JTAG port setup time	2		ns
t _{JPSU (TMS)}	TMS JTAG port setup time	3		ns
t _{JPH}	JTAG port hold time	5		ns
t _{JPCO}	JTAG port clock to output		12 ⁽⁹⁰⁾	ns
t _{JPZX}	JTAG port high impedance to valid output		14 ⁽⁹⁰⁾	ns
t _{JPXZ}	JTAG port valid output to high impedance		14 ⁽⁹⁰⁾	ns

Table 1-62: HPS JTAG Timing Parameters and Values for Arria V Devices

Configuration Specifications

This section provides configuration specifications and timing for Arria V devices.

POR Specifications

Table 1-63: Fast and Standard POR Delay Specification for Arria V Devices

POR Delay	Minimum	Maximum	Unit
Fast	4	12 ⁽⁹¹⁾	ms

⁽⁹⁰⁾ A 1-ns adder is required for each V_{CCIO_HPS} voltage step down from 3.0 V. For example, t_{JPCO} = 13 ns if V_{CCIO_HPS} of the TDO I/O bank = 2.5 V, or 14 ns if it equals 1.8 V.

⁽⁹¹⁾ The maximum pulse width of the fast POR delay is 12 ms, providing enough time for the PCIe hard IP to initialize after the POR trip.



1-80 AS Configuration Timing

Symbol	Parameter	Minimum	Maximum	Unit
t _{CD2CU}	CONF_DONE high to CLKUSR enabled	$4 \times maximum$ DCLK period	—	—
t _{CD2UMC}	CONF_DONE high to user mode with CLKUSR option on	t_{CD2CU} + ($T_{init} \times CLKUSR$ period)		
T _{init}	Number of clock cycles required for device initialization	8,576		Cycles

Related Information

FPP Configuration Timing

Provides the FPP configuration timing waveforms.

AS Configuration Timing

Table 1-68: AS Timing Parameters for AS ×1 and ×4 Configurations in Arria V Devices

The minimum and maximum numbers apply to both the internal oscillator and CLKUSR when either one is used as the clock source for device configuration.

The t_{CF2CD} , t_{CF2ST0} , t_{CFG} , t_{STATUS} , and t_{CF2ST1} timing parameters are identical to the timing parameters for passive serial (PS) mode listed in PS Timing Parameters for Arria V Devices table. You can obtain the t_{CF2ST1} value if you do not delay configuration by externally holding nSTATUS low.

Symbol	Parameter	Minimum	Maximum	Unit
t _{CO}	DCLK falling edge to the AS_DATA0/ASDO output	—	2	ns
t _{SU}	Data setup time before the falling edge on DCLK	1.5		ns
t _{DH}	Data hold time after the falling edge on DCLK	0	_	ns
t _{CD2UM}	CONF_DONE high to user mode	175	437	μs
t _{CD2CU}	CONF_DONE high to CLKUSR enabled	$4 \times \text{maximum DCLK period}$	_	_
t _{CD2UMC}	CONF_DONE high to user mode with CLKUSR option on	t_{CD2CU} + ($T_{init} \times CLKUSR$ period)	_	—
T _{init}	Number of clock cycles required for device initialization	8,576		Cycles



Symbol	Description	Condition	Minimum ⁽¹¹⁴⁾	Typical	Maximum ⁽¹¹⁴⁾	Unit
V _{CCPT}	Power supply for programmable power technology	—	1.45	1.50	1.55	V
V _{CC_AUX}	Auxiliary supply for the programmable power technology	_	2.375	2.5	2.625	V
V _{CCPD} (116	I/O pre-driver (3.0 V) power supply	_	2.85	3.0	3.15	V
)	I/O pre-driver (2.5 V) power supply	_	2.375	2.5	2.625	V
	I/O buffers (3.0 V) power supply	_	2.85	3.0	3.15	V
	I/O buffers (2.5 V) power supply	_	2.375	2.5	2.625	V
	I/O buffers (1.8 V) power supply	_	1.71	1.8	1.89	V
V _{CCIO}	I/O buffers (1.5 V) power supply	_	1.425	1.5	1.575	V
	I/O buffers (1.35 V) power supply	_	1.283	1.35	1.45	V
	I/O buffers (1.25 V) power supply	_	1.19	1.25	1.31	V
	I/O buffers (1.2 V) power supply		1.14	1.2	1.26	V
	Configuration pins (3.0 V) power supply	_	2.85	3.0	3.15	V
V _{CCPGM}	Configuration pins (2.5 V) power supply	_	2.375	2.5	2.625	V
	Configuration pins (1.8 V) power supply		1.71	1.8	1.89	V
V _{CCA} _	PLL analog voltage regulator power supply		2.375	2.5	2.625	V
V _{CCD} FPLL	PLL digital voltage regulator power supply	_	1.45	1.5	1.55	V
V _{CCBAT} (117	Battery back-up power supply (For design security volatile key register)		1.2		3.0	V

⁽¹¹⁴⁾ The power supply value describes the budget for the DC (static) power supply tolerance and does not include the dynamic tolerance requirements.
Refer to the PDN tool for the additional budget for the dynamic tolerance requirements.



⁽¹¹⁶⁾ V_{CCPD} must be 2.5 V when V_{CCIO} is 2.5, 1.8, 1.5, 1.35, 1.25 or 1.2 V. V_{CCPD} must be 3.0 V when V_{CCIO} is 3.0 V.

⁽¹¹⁷⁾ If you do not use the design security feature in Arria V GZ devices, connect V_{CCBAT} to a 1.2- to 3.0-V power supply. Arria V GZ power-on-reset (POR) circuitry monitors V_{CCBAT}. Arria V GZ devices do not exit POR if V_{CCBAT} is not powered up.

Hot Socketing

Table 2-14: Hot Socketing Specifications for Arria V GZ Devices

Symbol	Description	Maximum
I _{IOPIN (DC)}	DC current per I/O pin	300 µA
I _{IOPIN (AC)}	AC current per I/O pin	8 mA ⁽¹²⁴⁾
I _{XCVR-TX (DC)}	DC current per transceiver transmitter pin	100 mA
I _{XCVR-RX (DC)}	DC current per transceiver receiver pin	50 mA

Internal Weak Pull-Up Resistor

Table 2-15: Internal Weak Pull-Up Resistor for Arria V GZ Devices

All I/O pins have an option to enable the weak pull-up resistor except the configuration, test, and JTAG pins. The internal weak pull-down feature is only available for the JTAG TCK pin. The typical value for this internal weak pull-down resistor is approximately 25 k Ω .

Symbol	Description	V _{CCIO} Conditions (V) ⁽¹²⁵⁾	Value ⁽¹²⁶⁾	Unit
R _{PU}	Value of the I/O pin pull-up resistor before and during configuration, as well as user mode if you enable the programmable pull-up resistor option.	3.0 ±5%	25	kΩ
		2.5 ±5%	25	kΩ
		1.8 ±5%	25	kΩ
		1.5 ±5%	25	kΩ
		1.35 ±5%	25	kΩ
		1.25 ±5%	25	kΩ
		1.2 ±5%	25	kΩ

⁽¹²⁴⁾ The I/O ramp rate is 10 ns or more. For ramp rates faster than 10 ns, $|I_{IOPIN}| = C dv/dt$, in which C is the I/O pin capacitance and dv/dt is the slew rate.





 $^{^{(125)}}$ The pin pull-up resistance values may be lower if an external source drives the pin higher than V_{CCIO} .

 $^{^{(126)}}$ These specifications are valid with a ±10% tolerance to cover changes over PVT.

AV-51002 2017.02.10

	V _{IL(D}	_{C)} (V)	V _{IH(DC}	_{_)} (V)	V _{IL(AC)} (V)	V _{IH(AC)} (V)	V _{OL} (V)	V _{OH} (V)	Ι (ma Δ)	I (m A)
i/O Standard	Min	Max	Min	Max	Max	Min	Max	Min	i _{ol} (mA)	I _{oh} (MA)
SSTL-18 Class II	-0.3	V _{REF} – 0.125	V _{REF} + 0.125	V _{CCIO} + 0.3	V _{REF} – 0.25	V _{REF} + 0.25	0.28	V _{CCIO} – 0.28	13.4	-13.4
SSTL-15 Class I	—	V _{REF} – 0.1	V _{REF} + 0.1	—	V _{REF} – 0.175	V _{REF} + 0.175	$0.2 \times V_{ m CCIO}$	$0.8 \times V_{ m CCIO}$	8	-8
SSTL-15 Class II	_	V _{REF} – 0.1	V _{REF} + 0.1	—	V _{REF} – 0.175	V _{REF} + 0.175	$0.2 \times V_{ m CCIO}$	$0.8 \times V_{ m CCIO}$	16	-16
SSTL-135 Class I, II	_	V _{REF} – 0.09	V _{REF} + 0.09	—	V _{REF} – 0.16	V _{REF} + 0.16	0.2 * V _{CCIO}	0.8 * V _{CCIO}	_	-
SSTL-125 Class I, II	_	V _{REF} – 0.85	V _{REF} + 0.85	—	V _{REF} – 0.15	V _{REF} + 0.15	0.2 * V _{CCIO}	0.8 * V _{CCIO}	_	_
SSTL-12 Class I, II	_	V _{REF} – 0.1	V _{REF} + 0.1	—	V _{REF} – 0.15	V _{REF} + 0.15	0.2 * V _{CCIO}	0.8 * V _{CCIO}	—	_
HSTL-18 Class I		V _{REF} – 0.1	V _{REF} + 0.1	—	V _{REF} – 0.2	V _{REF} + 0.2	0.4	$V_{\rm CCIO}$ – 0.4	8	-8
HSTL-18 Class II		V _{REF} – 0.1	V _{REF} + 0.1	—	V _{REF} – 0.2	V _{REF} + 0.2	0.4	$V_{\rm CCIO}$ – 0.4	16	-16
HSTL-15 Class I	_	V _{REF} – 0.1	V _{REF} + 0.1	_	V _{REF} - 0.2	V _{REF} + 0.2	0.4	V _{CCIO} – 0.4	8	-8
HSTL-15 Class II	_	V _{REF} – 0.1	V _{REF} + 0.1	—	V _{REF} - 0.2	V _{REF} + 0.2	0.4	V _{CCIO} – 0.4	16	-16
HSTL-12 Class I	-0.15	V _{REF} – 0.08	V _{REF} + 0.08	V _{CCIO} + 0.15	V _{REF} – 0.15	V _{REF} + 0.15	$0.25 \times V_{ m CCIO}$	$0.75 \times V_{ m CCIO}$	8	-8
HSTL-12 Class II	-0.15	V _{REF} – 0.08	V _{REF} + 0.08	V _{CCIO} + 0.15	V _{REF} – 0.15	V _{REF} + 0.15	$0.25 \times V_{ m CCIO}$	$0.75 \times V_{ m CCIO}$	16	-16
HSUL-12	—	V _{REF} – 0.13	V _{REF} + 0.13	_	V _{REF} - 0.22	V_{REF} + 0.22	$0.1 \times V_{CCIO}$	$0.9 \times V_{CCIO}$	_	_

Arria V GZ Device Datasheet

Altera Corporation



Core Performance Specifications

Clock Tree Specifications

Table 2-33: Clock Tree Performance for Arria V GZ Devices

Symbol	Perfo	llait	
зульог	C3, I3L	C3, I3L C4, I4	
Global and Regional Clock	650	580	MHz
Periphery Clock	500	500	MHz

PLL Specifications

Table 2-34: PLL Specifications for Arria V GZ Devices

Symbol	Parameter	Min	Тур	Мах	Unit
f (167)	Input clock frequency (C3, I3L speed grade)	5	—	800	MHz
IIN	Input clock frequency (C4, I4 speed grade)	5	—	650	MHz
f _{INPFD}	Input frequency to the PFD	5	_	325	MHz
f _{FINPFD}	Fractional Input clock frequency to the PFD	50	_	160	MHz
f	PLL VCO operating range (C3, I3L speed grade)	600	_	1600	MHz
IVCO (III)	PLL VCO operating range (C4, I4 speed grade)	600	—	1300	MHz
t _{EINDUTY}	Input clock or external feedback clock input duty cycle	40	_	60	%

⁽¹⁶⁷⁾ This specification is limited in the Quartus II software by the I/O maximum frequency. The maximum I/O frequency is different for each I/O standard.

⁽¹⁶⁸⁾ The VCO frequency reported by the Quartus II software in the **PLL Usage Summary** section of the compilation report takes into consideration the VCO post-scale counter K value. Therefore, if the counter K has a value of 2, the frequency reported can be lower than the f_{VCO} specification.

Arria V GZ Device Datasheet



2-44 Periphery Performance

Description	Min	Тур	Мах	Unit
Diode ideality factor	1.006	1.008	1.010	—

Periphery Performance

I/O performance supports several system interfaces, such as the **LVDS** high-speed I/O interface, external memory interface, and the **PCI/PCI-X** bus interface. General-purpose I/O standards such as 3.3-, 2.5-, 1.8-, and 1.5-**LVTTL/LVCMOS** are capable of a typical 167 MHz and 1.2-**LVCMOS** at 100 MHz interfacing frequency with a 10 pF load.

Note: The actual achievable frequency depends on design- and system-specific factors. Ensure proper timing closure in your design and perform HSPICE/IBIS simulations based on your specific design and system setup to determine the maximum achievable frequency in your system.

High-Speed I/O Specification

High-Speed Clock Specifications

Table 2-39: High-Speed Clock Specifications for Arria V GZ Devices

When J = 3 to 10, use the serializer/deserializer (SERDES) block.

When J = 1 or 2, bypass the SERDES block.

For LVDS applications, you must use the PLLs in integer PLL mode.

Arria V GZ devices support the following output standards using true LVDS output buffer types on all I/O banks.

- True RSDS output standard with data rates of up to 230 Mbps
- True mini-LVDS output standard with data rates of up to 340 Mbps



2-50 Soft CDR Mode High-Speed I/O Specifications

Standard	Training Pattern	Number of Data Transitions in One Repetition of the Training Pattern	Number of Repetitions per 256 Data Transitions (201)	Maximum
Parallel Rapid I/O	00001111	2	128	640 data transitions
	10010000	4	64	640 data transitions
Miscellaneous	10101010	8	32	640 data transitions
	01010101	8	32	640 data transitions

Soft CDR Mode High-Speed I/O Specifications

Table 2-44: High-Speed I/O Specifications for Arria V GZ Devices

When J = 3 to 10, use the serializer/deserializer (SERDES) block.

When J = 1 or 2, bypass the SERDES block.

Symbol	Conditions	C3, I3L C4, I4				C3, I3L		C4, 14			Unit
		Min	Тур	Max	Min	Тур	Max				
Soft-CDR ppm tolerance	—	_	_	300	_	_	300	± ppm			





⁽²⁰¹⁾ This is the number of repetitions for the stated training pattern to achieve the 256 data transitions.

JTAG Configuration Specifications

Table 2-54: JTAG Timing Parameters and Values for Arria V GZ Devices	;
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Symbol	Description	Min	Мах	Unit
t _{JCP}	TCK clock period	30		ns
t _{JCP}	TCK clock period	167 (203)		ns
t _{JCH}	TCK clock high time	14		ns
t _{JCL}	TCK clock low time	14		ns
t _{JPSU (TDI)}	TDI JTAG port setup time	2		ns
t _{JPSU (TMS)}	TMS JTAG port setup time	3		ns
t _{JPH}	JTAG port hold time	5		ns
t _{JPCO}	JTAG port clock to output	_	11 (204)	ns
t _{JPZX}	JTAG port high impedance to valid output		14 (204)	ns
t _{JPXZ}	JTAG port valid output to high impedance	_	14 (204)	ns

Fast Passive Parallel (FPP) Configuration Timing

DCLK-to-DATA[] Ratio (r) for FPP Configuration

FPP configuration requires a different DCLK-to-DATA[] ratio when you turn on encryption or the compression feature.

Arria V GZ Device Datasheet

Altera Corporation



⁽²⁰³⁾ The minimum TCK clock period is 167 ns if VCCBAT is within the range 1.2V-1.5V when you perform the volatile key programming.

⁽²⁰⁴⁾ A 1-ns adder is required for each V_{CCIO} voltage step down from 3.0 V. For example, $t_{IPCO} = 12$ ns if V_{CCIO} of the TDO I/O bank = 2.5 V, or 13 ns if it equals 1.8 V.

FPP Configuration Timing when DCLK to DATA[] > 1

Figure 2-8: FPP Configuration Timing Waveform When the DCLK-to-DATA[] Ratio is >1,

t_{CF2ST1} tcfg ;↔ nCONFIG ŤĊF2CK nSTATUS (3) 🕳 tstatus tCF2ST0 CONF_DONE (4) TCL tCH tsT2CK ŤĊF2CD (8) DCLK (6) (7) 1 2 ••• r 2 ••• r 1 \mathbf{D} (5) tCLK DATA[31..0] (8) Word 0 Word User Mode Word 3 • • • Word (n-1) tDH tDH tpsy High-Z User I/O User Mode INIT DONE (9) tCD2UM

Timing when using a MAX II device, MAX V device, or microprocessor as an external host.

Notes:

- 1. To find out the DCLK-to-DATA[] ratio for your system, refer to the "DCLK-to-DATA[] Ratio for Arria V GZ Devices" table.
- 2. The beginning of this waveform shows the device in user mode. In user mode, nCONFIG, nSTATUS, and CONF_DONE are at logic high levels. When nCONFIG is pulled low, a reconfiguration cycle begins.
- 3. After power-up, the Arria V GZ device holds nSTATUS low for the time as specified by the POR delay.
- 4. After power-up, before and during configuration, CONF_DONE is low.
- 5. Do not leave DCLK floating after configuration. DCLK is ignored after configuration is complete. It can toggle high or low if required.
- 6. "r" denotes the DCLK-to-DATA[] ratio. For the DCLK-to-DATA[] ratio based on the decompression and the design security feature enable settings, refer to the "DCLK-to-DATA[] Ratio for Arria V GZ Devices" table.
- 7. If needed, pause DCLK by holding it low. When DCLK restarts, the external host must provide data on the DATA[31.0] pins prior to sending the first DCLK rising edge.
- 8. To ensure a successful configuration, send the entire configuration data to the Arria V GZ device. CONF_DONE is released high after the Arria V GZ device receives all the configuration data successfully. After CONF_DONE goes high, send two additional falling edges on DCLK to begin initialization and enter user mode.
- 9. After the option bit to enable the INIT_DONE pin is configured into the device, the INIT_DONE goes low.





Term	Definition		
	Single-Ended Waveform Positive Channel (p) = V_{0H} V_{0D} Negative Channel (n) = V_{0L} V_{CM} Ground		
	Differential Waveform V_{0D} V_{0D} V_{0D} V_{0D}		
f _{HSCLK}	Left and right PLL input clock frequency.		
f _{HSDR}	High-speed I/O block—Maximum and minimum LVDS data transfer rate (f _{HSDR} = 1/TUI), non-DPA.		
f _{hsdrdpa}	High-speed I/O block—Maximum and minimum LVDS data transfer rate (f _{HSDRDPA} = 1/TUI), DPA.		
J	High-speed I/O block—Deserialization factor (width of parallel data bus).		







